

<b>Notice of References Cited</b>	Application/Control No. 10/694,774	Applicant(s)/Patent Under Reexamination HIRANO, YUJI	
	Examiner JYOTHSNA A. VENKAT Ph. D	Art Unit 1615	Page 1 of 1

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	M	US-			

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**NON-PATENT DOCUMENTS**

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